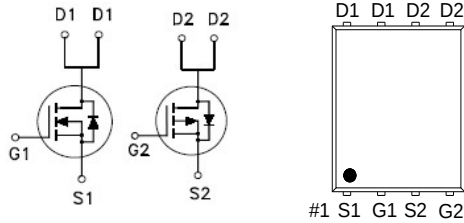


PRODUCT SUMMARY

	$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
Q2	-100V	180m Ω	-10A
Q1	100V	110m Ω	9A



G. GATE
D. DRAIN
S. SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25\text{ }^{\circ}\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	Q2	Q1	UNITS
Drain-Source Voltage		V_{DS}	-100	100	V
Gate-Source Voltage		V_{GS}	± 25	± 20	V
Continuous Drain Current	$T_C = 25\text{ }^{\circ}\text{C}$	I_D	-10	9	A
	$T_C = 100\text{ }^{\circ}\text{C}$		-6.5	5.7	
Pulsed Drain Current ¹		I_{DM}	-40	25	
Continuous Drain Current ³	$T_A = 25\text{ }^{\circ}\text{C}$	I_D	-2.7	3	
	$T_A = 70\text{ }^{\circ}\text{C}$		-2.2	2.5	
Avalanche Current		I_{AS}	-11	6	
Avalanche Energy	$L = 1\text{mH}$	E_{AS}	61	18	mJ
Power Dissipation	$T_C = 25\text{ }^{\circ}\text{C}$	P_D	42	21	W
	$T_C = 100\text{ }^{\circ}\text{C}$		17	8	
Power Dissipation ³	$T_A = 25\text{ }^{\circ}\text{C}$	P_D	3	2.5	W
	$T_A = 70\text{ }^{\circ}\text{C}$		1.9	1.6	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150		$^{\circ}\text{C}$

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE		SYMBOL		TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$t \leq 10\text{s}$	$R_{\theta JA}$	Q2		42	$^{\circ}\text{C} / \text{W}$
			Q1		50	
Junction-to-Ambient ²	Steady-State	$R_{\theta JA}$	Q2		63	
			Q1		73	
Junction-to-Case		$R_{\theta JC}$	Q2		3	
			Q1		6	

¹Pulse width limited by maximum junction temperature $T_{J(MAX)}=150^{\circ}\text{C}$.

²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$. The value in any given application depends on the user's specific board design.

³The Power dissipation is based on $R_{\theta JA} t \leq 10\text{s}$ value.

ELECTRICAL CHARACTERISTICS (T_J = 25 °C, Unless Otherwise Noted)

PARAMETER	SYMBOL		TEST CONDITIONS	LIMITS			UNIT		
				MIN	TYP	MAX			
STATIC									
Drain-Source Breakdown Voltage	V _{(BR)DSS}		V _{GS} = 0V, I _D = -250μA	Q2	-100		V		
			V _{GS} = 0V, I _D = 250μA	Q1	100				
Gate Threshold Voltage	V _{GS(th)}		V _{DS} = V _{GS} , I _D = -250μA	Q2	-1.3	-1.8	-2.3	V	
			V _{DS} = V _{GS} , I _D = 250μA	Q1	1.3	1.8	3		
Gate-Body Leakage	I _{GSS}		V _{DS} = 0V, V _{GS} = ±25V	Q2			±100	nA	
			V _{DS} = 0V, V _{GS} = ±20V	Q1			±100		
Zero Gate Voltage Drain Current	I _{DSS}		V _{DS} = -80V, V _{GS} = 0V	Q2			-1	μA	
			V _{DS} = 80V, V _{GS} = 0V	Q1			1		
			V _{DS} = -80V, V _{GS} = 0V, T _J = 55 °C	Q2			-10		
			V _{DS} = 80V, V _{GS} = 0V, T _J = 55 °C	Q1			10		
Drain-Source On-State Resistance ¹	R _{DS(ON)}		V _{GS} = -4.5V, I _D = -5A	Q2		173	190	mΩ	
			V _{GS} = 4.5V, I _D = 6A	Q1		86	120		
			V _{GS} = -10V, I _D = -5A	Q2		159	180		
			V _{GS} = 10V, I _D = 6A	Q1		80	110		
Forward Transconductance ¹	g _{fs}		V _{DS} = -5V, I _D = -5A	Q2		19		S	
			V _{DS} = 5V, I _D = 6A	Q1		30			
DYNAMIC									
Input Capacitance	C _{iss}		Q2 V _{GS} = 0V, V _{DS} = -25V f = 1MHz Q1 V _{GS} = 0V, V _{DS} = 25V f = 1MHz	Q2	1232	1540	1840	pF	
Output Capacitance	C _{oss}			Q1	492	616	739		
				Q2	90	113	135		
				Q1	44	55	66		
Reverse Transfer Capacitance	C _{rss}		Q2	46	77	108	pF		
			Q1	18	31	43			
Gate Resistance	R _g		V _{GS} = 0V, V _{DS} = 0V, f = 1MHz	Q2	1.9	3.8	5.7	Ω	
				Q1	0.8	1.5	2.3		
Total Gate Charge ²	Q _g	V _{GS} = 10V	Q2 V _{DS} = -50V V _{GS} = -10V, I _D = -5A Q1 V _{DS} = 50V V _{GS} = 10V, I _D = 6A	Q2	23	29	34.8	nC	
				Q1	11	14	16.8		
				V _{GS} = 4.5V	Q2	12	15		18
					Q1	6.4	8		9.6
Gate-Source Charge ²	Q _{gs}			Q2	3.3	4.1	4.9		nC
				Q1	1.4	1.8	2.2		
Gate-Drain Charge ²	Q _{gd}			Q2	4.3	7.1	9.9		nC
				Q1	2.6	4.3	6		

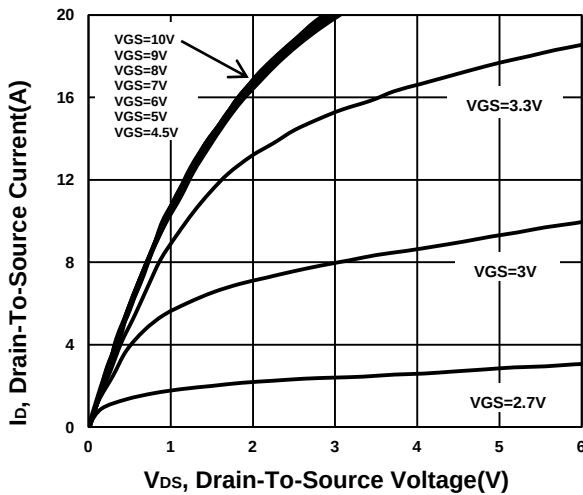
Turn-On Delay Time ²	t _{d(on)}	Q2 , V _{DS} = -50V I _D ≅ -5A V _{GS} = -10V, R _{GEN} =6Ω	Q2		17		nS
			Q1		11		
Rise Time ²	t _r		Q2		20		
			Q1		21		
Turn-Off Delay Time ²	t _{d(off)}	Q2		59			
		Q1		27			
Fall Time ²	t _f	Q2		41			
		Q1		41			
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T _J = 25 °C)							
Continuous Current	I _S		Q2			-10	A
			Q1			9	
Forward Voltage ¹	V _{SD}	I _F = -5A V _{GS} = 0V	Q2			-1.2	V
		I _F = 6A, V _{GS} = 0V	Q1			1.4	
Reverse Recovery Time	t _{rr}	Q2 I _F = -5A dl _F /dt = 100A / μS	Q2	21	43	64	nS
			Q1	11	23	34	
Reverse Recovery Charge	Q _{rr}	Q1 I _F = 6A, dl _F /dt = 100A / μS	Q2	43	87	130	nC
			Q1	12	25	37	

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.

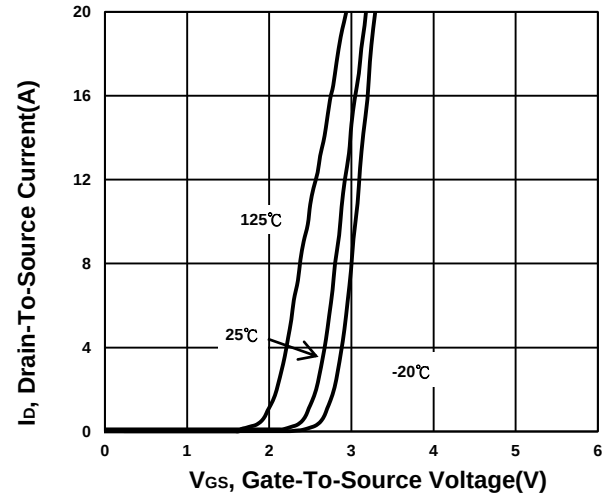
²Independent of operating temperature.

TYPICAL PERFORMANCE CHARACTERISTICS N-CHANNEL

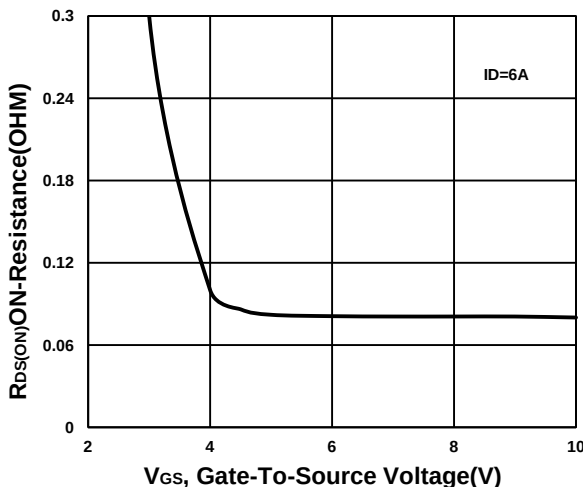
Output Characteristics



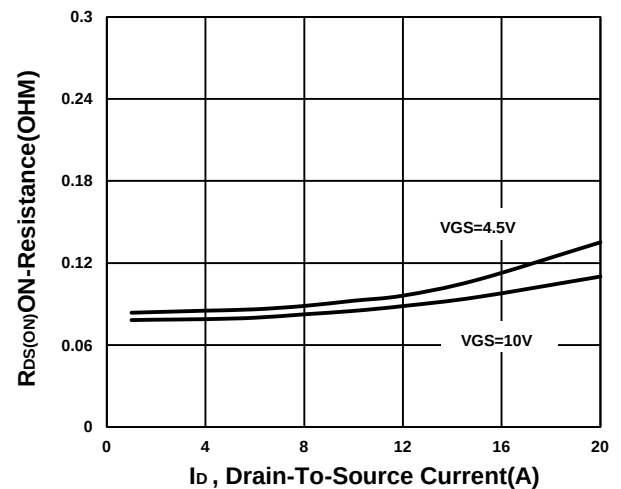
Transfer Characteristics



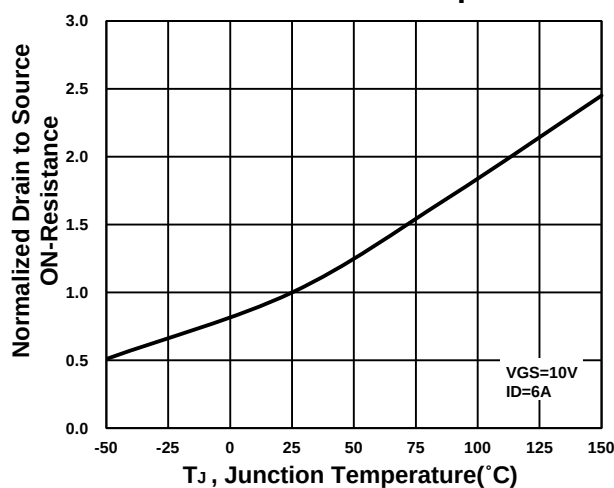
On-Resistance VS Gate-To-Source Voltage



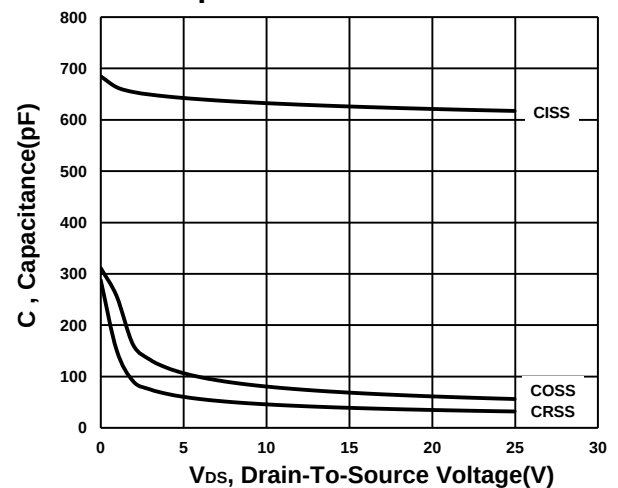
On-Resistance VS Drain Current



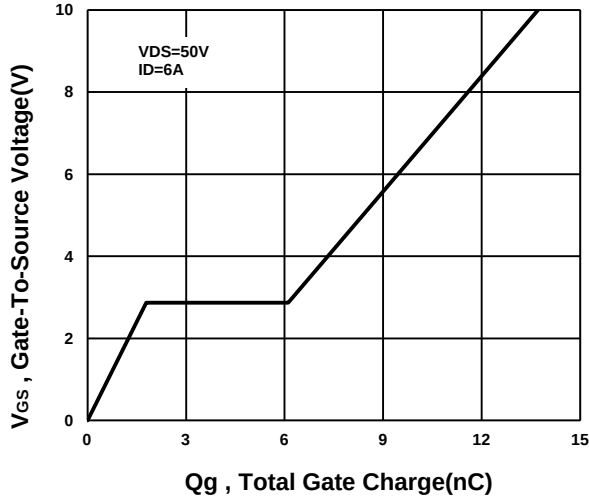
On-Resistance VS Temperature



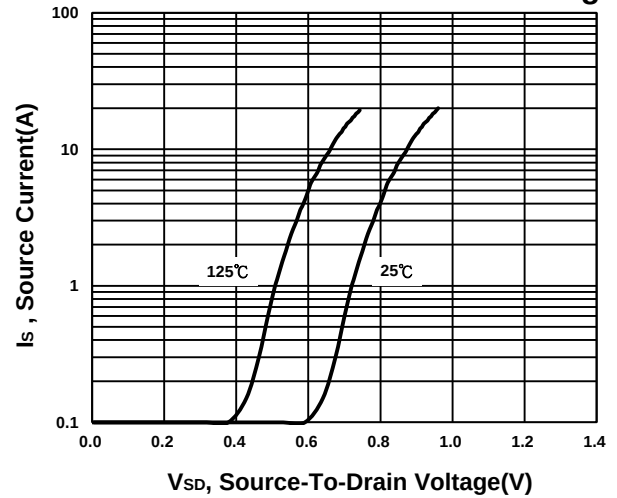
Capacitance Characteristic



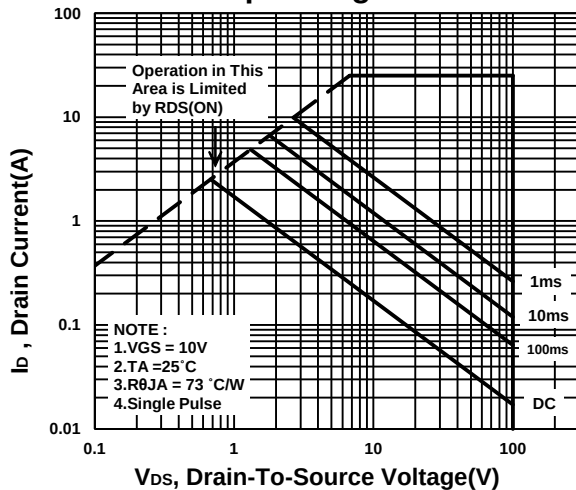
Gate charge Characteristics



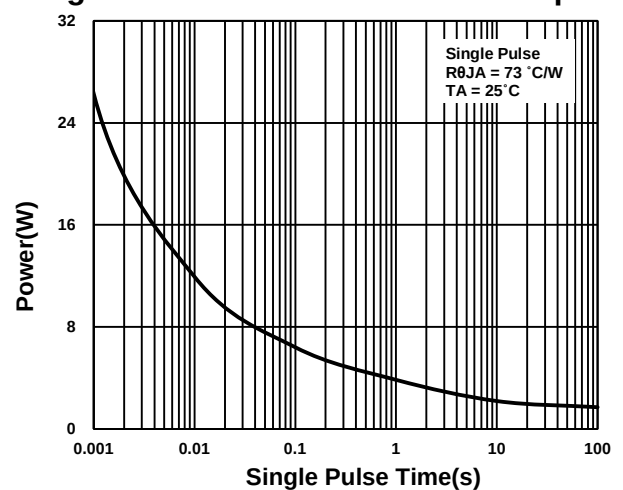
Source-Drain Diode Forward Voltage



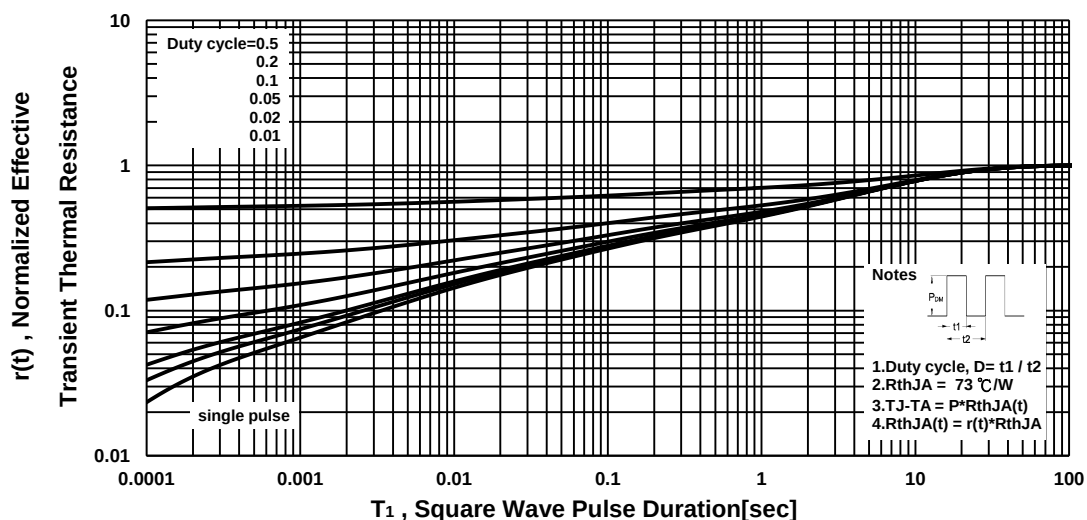
Safe Operating Area



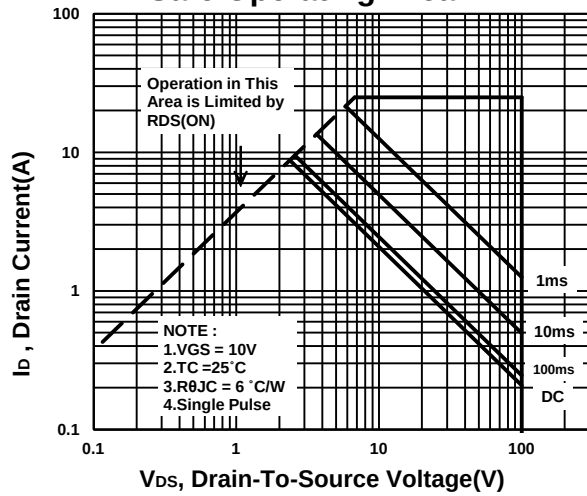
Single Pulse Maximum Power Dissipation



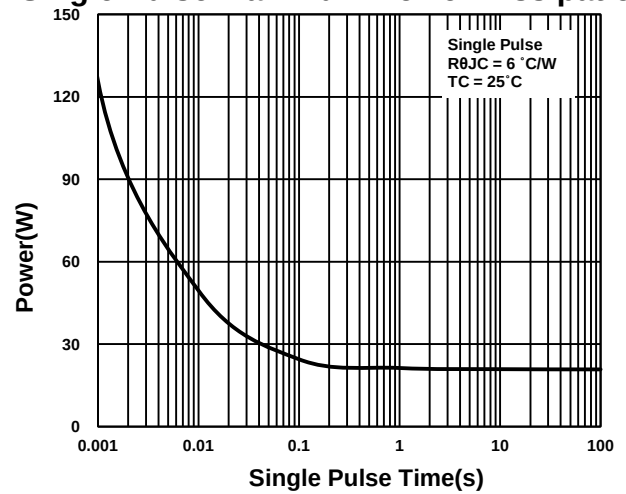
Transient Thermal Response Curve



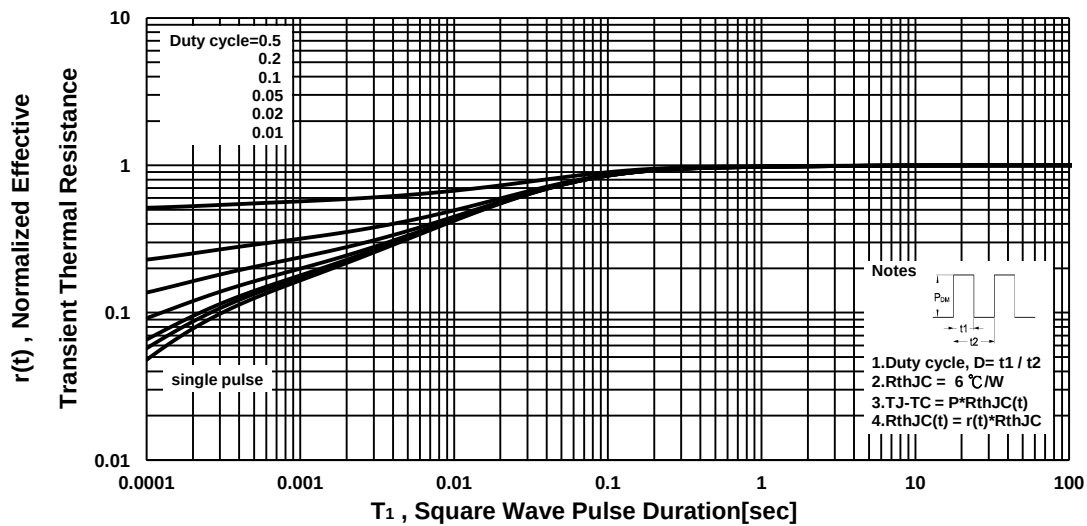
Safe Operating Area



Single Pulse Maximum Power Dissipation

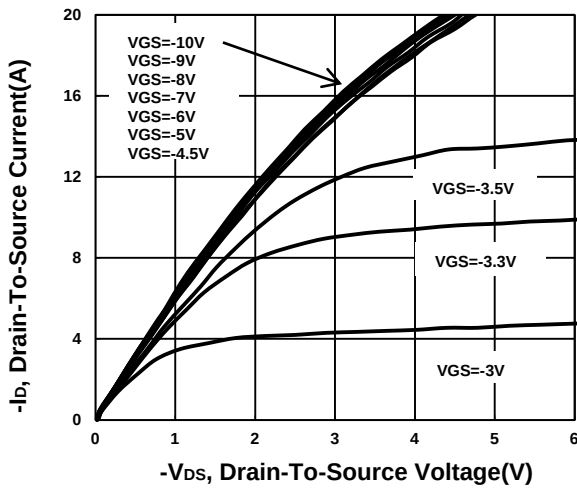


Transient Thermal Response Curve

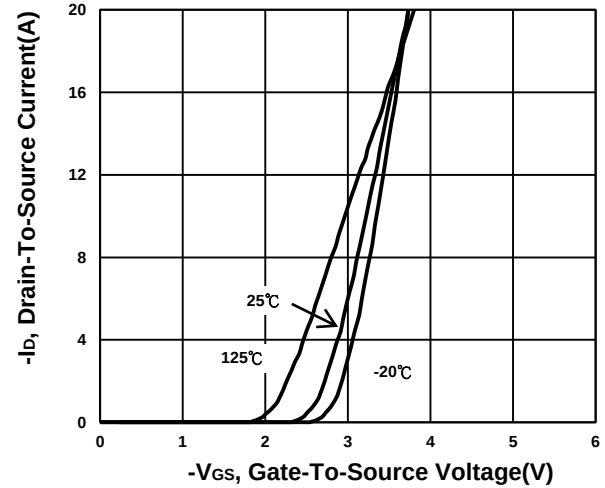


P-CHANNEL

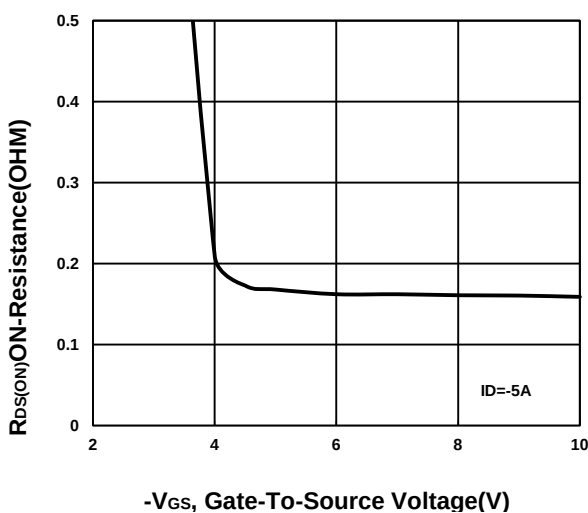
Output Characteristics



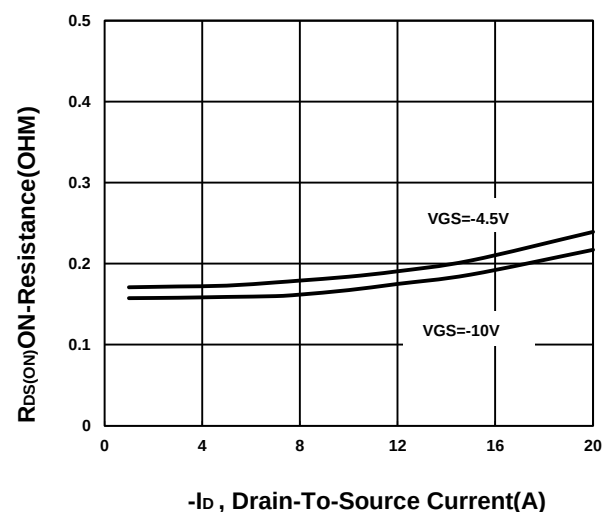
Transfer Characteristics



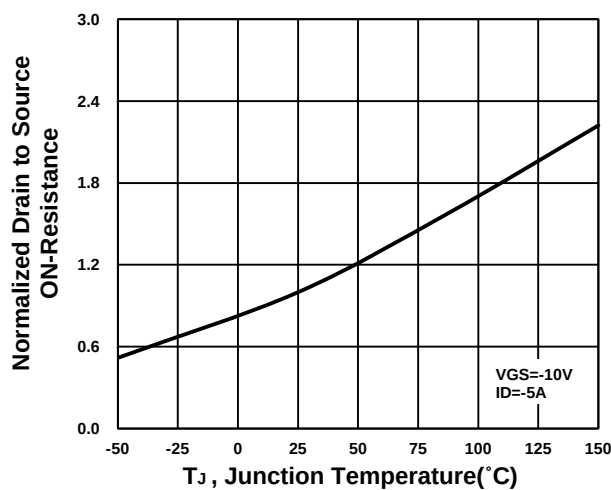
On-Resistance VS Gate-To-Source Voltage



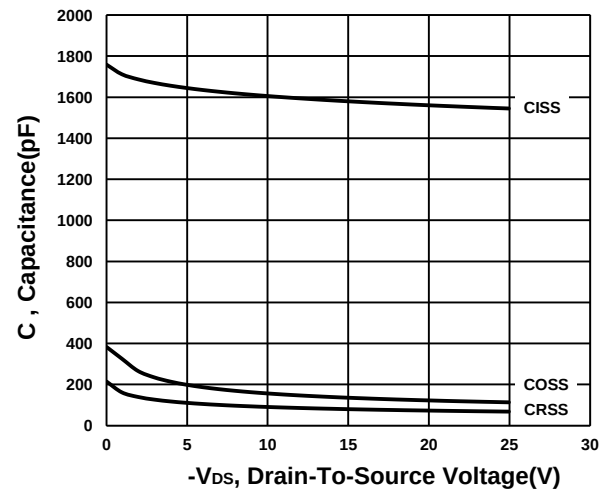
On-Resistance VS Drain Current



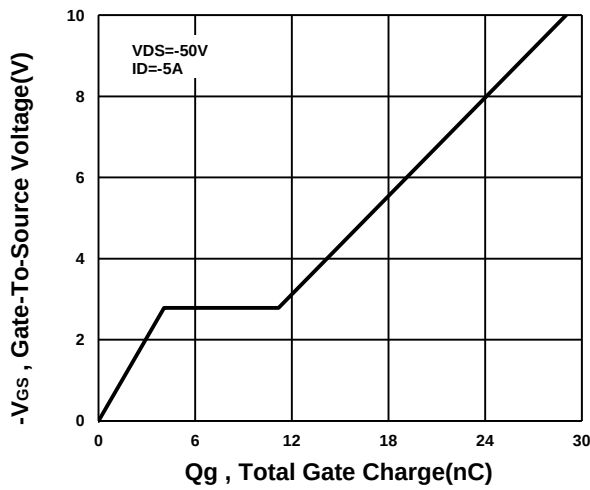
On-Resistance VS Temperature



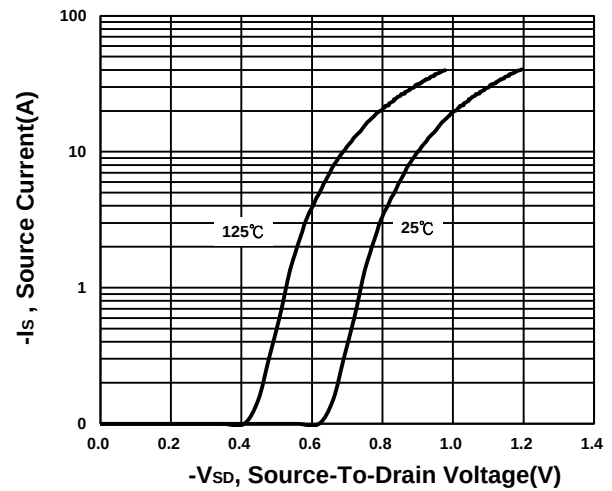
Capacitance Characteristic



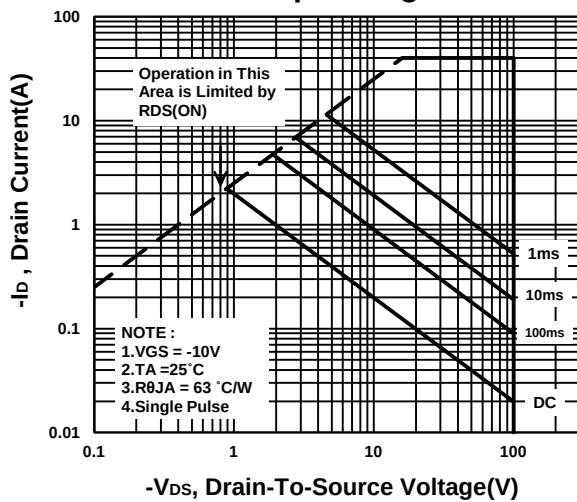
Gate charge Characteristics



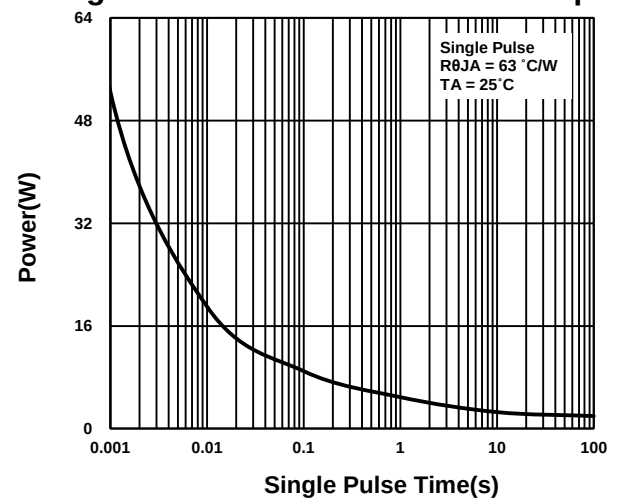
Source-Drain Diode Forward Voltage



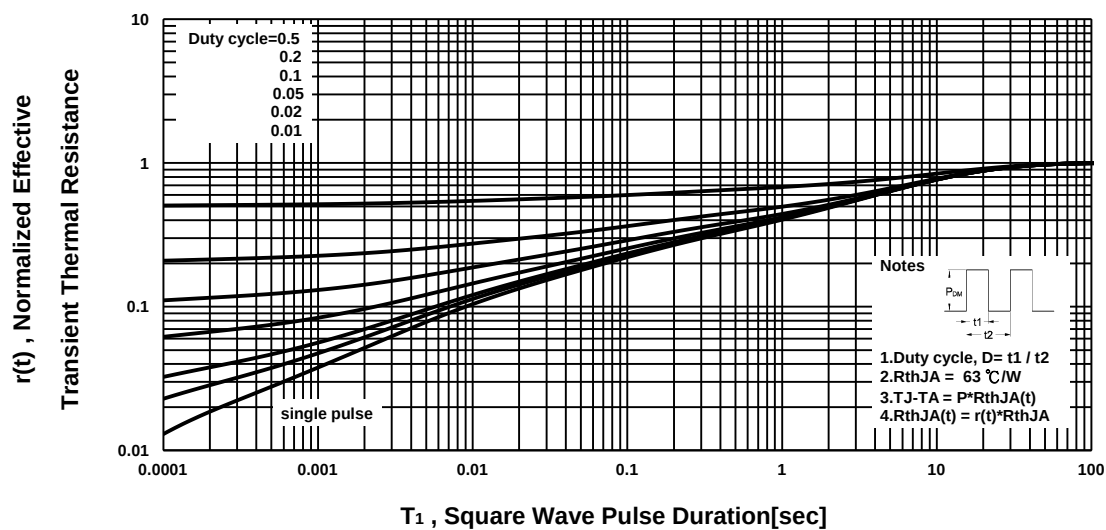
Safe Operating Area



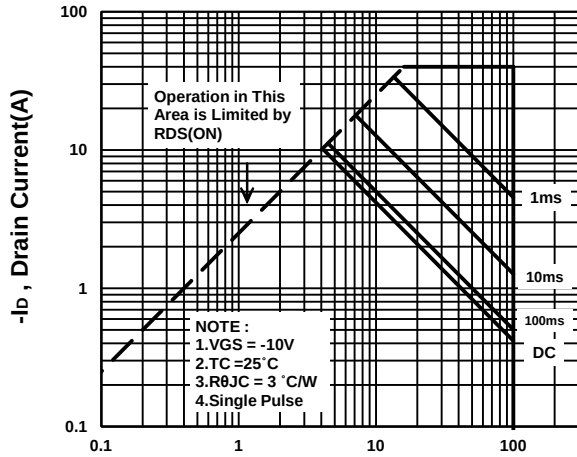
Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

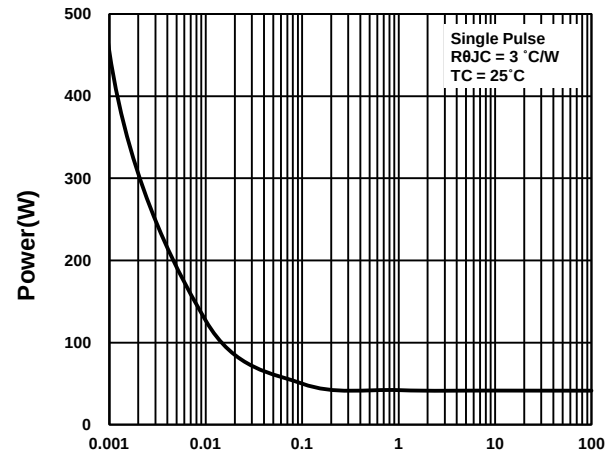


Safe Operating Area



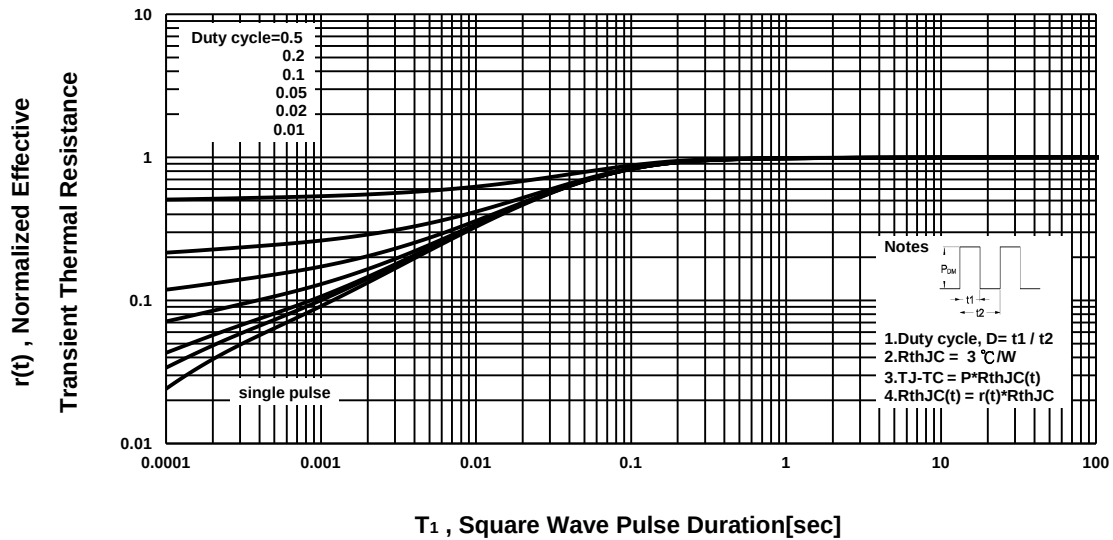
$-V_{DS}$, Drain-To-Source Voltage(V)

Single Pulse Maximum Power Dissipation



Single Pulse Time(s)

Transient Thermal Response Curve



T_1 , Square Wave Pulse Duration[sec]